Matterhorn, a high flux PAUL SCHERRER INSTITUT detector for 4th generation synchrotrons

A. Mozzanica^{*}, R. Barten, F. Baruffaldi, A. Bergamaschi, M. Brückner, M. Carulla, R. Dinapoli, S. Ebner, E. Fröjdh, D. Greiffenberg, S. Hasanaj, J. Heymes, V. Hinger, T. King, P. Kozlowski, C. Lopez Cuenca, D. Mezza, K. Moustakas, A. Mozzanica, K. Paton, C. Ruder, B. Schmitt, D. Thattil, X. Xie J. Zhang

Paul Scherrer Institut (PSI), Photon Science Division Detector Group, CH-5232 Villigen PSI, Switzerland

PM24, Elba, May 2024, *aldo.mozzanica@psi.ch

Introduction to Matterhorn

Why a high flux photon counter:

- 4 generation sources are delivering low emittances and increased brilliances [1]
- charge integrating detector (e.g. Jungfrau, CITIUS) can cope with very high fluxes, but deployment and operation can be challenging



a high rate single photon counting (SPC) detector could be the workhorse for many beamlines

Final system performances:

- 10KHz readout at 16b/pixel
- 250eV to 80keV energy range with special sensors (4keV-20keV with Silicon)
- 20ns gating, multiple gating.

Extending the count rate with multiple threshold

Basic Idea[2]:

up to 4 counters per pixel, read them out then sum them.



• with threshold adjustment, works well with poissonian distributed arrival time What can be achieved:



- 90% efficiency at 20Mcps with 4 counters,
- starting from 2Mcps with a single thresold

simulated rate response with time constant from single counter measurement

Small scale ASIC:

- quasi-final pixel design
- advanced digital periphery



The MH0.2 prototype

Digital periphery:

- synthesized from VHDL (analog on top)
- controlling DACs, trimbits, PLL and pixel counter configurations
- receiving pixel matrix data
- converting to 8b/10b encoding
- 3.125Gbps DDR serializer feeding the offchip CML drivers.



 links work reliably (BER<10⁻¹⁵) • 64b/66b version for the full scale ASIC under design

R. Dinapoli (b. 1971)

Prototype results

noise ENC <80e⁻ in standard settings

[1] A. Streun et al, Journal of Synchrotron Radiation, 25(3) (2018) [2] Andrä, M. et al., Journal of Instrumentation, 14(11), C11028 (2019)